

OCT 08 2006

SHEET 1 OF 1

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
291795US2PCTSERIAL NO.
10/580,822

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Janick BIGARRE, et al.

FILING DATE

May 26, 2006

GROUP

U.S. PATENT DOCUMENTS

| EXAMINER INITIAL | | DOCUMENT NUMBER | DATE | NAME | CLASS | SUB CLASS | FILING DATE IF APPROPRIATE |
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

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|----------|--------------------|---|
| /MLB/ | AV | BIGARRE J. et al., "TRAPPING OF ELECTRICAL CHARGES AND LASER DAMAGE", PROCEEDINGS OF SPIE- THE INTERNATIONAL SOCIETY FOR OPTICAL ENGINEERING, vol. 4932, pages 258-267, XP002289327, 2003 |
| /MLB/ | AW | KOZLOWSKI M. R. et al., "LUMINESCENCE INVESTIGATION OF SiO ₂ SURFACES DAMAGED BY 0.35 mm LASER ILLUMINATION", SPIE, vol. 3902, pages 138-144, XP002289328, 2000 |
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| /MLB/ | AY | STEVENS KALCEFF M. A., "CATHODOLUMINESCENCE MICROCHARACTERIZATION OF THE DEFECT STRUCTURE OF IRRADIATED HYDRATED AND ANHYDROUS FUSED SILICON DIOXIDE", PHYSICAL REVIEW B, vol. 57, pages 5674-5683, XP002289330, 1998 |
| /MLB/ | AZ | REICHLING M., "NANOSECOND UV LASER PULSE INTERACTIONS WITH DIELECTRIC SINGLE CRYSTALS", PROCEEDINGS OF THE SPIE- THE INTERNATIONAL SOCIETY FOR OPTICAL ENGINEERING, vol. 3274, pages 2-9, XP002289331, 1998 |
| | | <input type="checkbox"/> Additional References sheet(s) attached |
| Examiner | /Manuel L. Barbee/ | Date Considered 09/29/2007 |

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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